



US00D675336S

(12) **United States Design Patent**
Laverack et al.

(10) **Patent No.:** **US D675,336 S**
(45) **Date of Patent:** **** Jan. 29, 2013**

(54) **TESTING APPARATUS**

(75) Inventors: **Paul Laverack**, Milton Keynes (GB);
Richard Luxton, Leighton Buzzard
(GB); **Robin Brown**, Cambs (GB)

(73) Assignee: **SPD Swiss Precision Diagnostics
GmbH**, Geneva (CH)

(**) Term: **14 Years**

(21) Appl. No.: **29/389,578**

(22) Filed: **Apr. 13, 2011**

(30) **Foreign Application Priority Data**

Oct. 13, 2010 (EM) 001767732-0007
Oct. 13, 2010 (EM) 001767732-0008

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.** **D24/223**

(58) **Field of Classification Search** D24/216–217,
D24/219, 222–226, 227, 231, 232, 107, 169,
D24/186; D10/81; 422/400–404, 408, 430,
422/68.1, 69, 500; 435/287.1, 287.3, 287.4,
435/288.1, 288.3, 288.7, 806

See application file for complete search history.

(56) **References Cited**

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D607,347 S * 1/2010 Goh et al. D10/81
D648,029 S * 11/2011 Presta et al. D24/169

* cited by examiner

Primary Examiner — Anhdao Doan

(74) *Attorney, Agent, or Firm* — Haynes and Boone, LLP

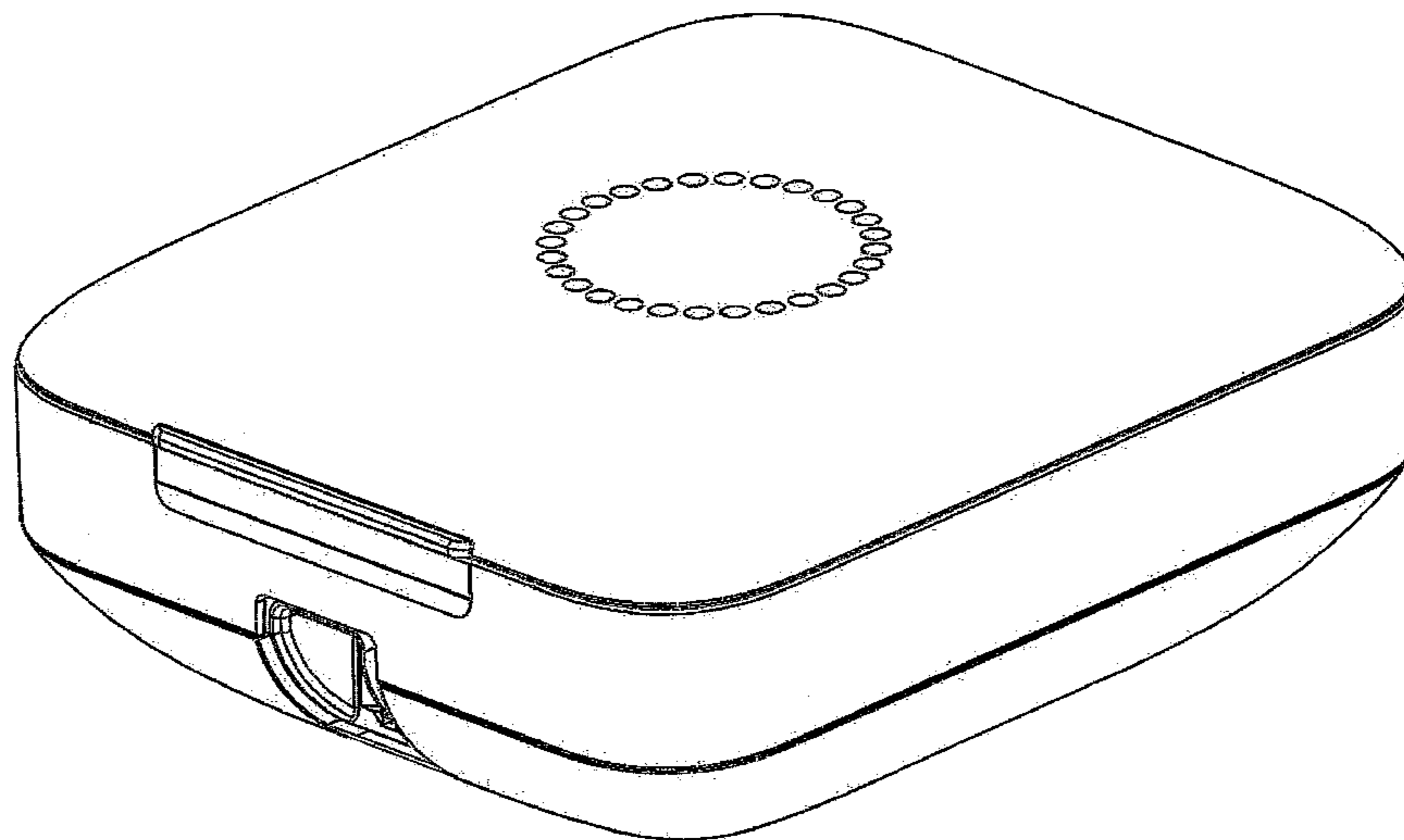
(57) **CLAIM**

The ornamental design for a testing apparatus, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a testing apparatus showing our new design, the perspective view of FIG. 1 showing the testing apparatus in a closed configuration;
FIG. 2 is a front elevational view of the testing apparatus in the closed configuration;
FIG. 3 is a left side elevational view of the testing apparatus in the closed configuration;
FIG. 4 is a rear elevational view of the testing apparatus in the closed configuration;
FIG. 5 is a top plan view of the testing apparatus in the closed configuration;
FIG. 6 is a bottom plan view of the testing apparatus in the closed configuration;
FIG. 7 is another perspective view of the testing apparatus in the closed configuration, and further includes environmental structure illustrated in broken lines;
FIG. 8 is a perspective view showing the testing apparatus in an open configuration;
FIG. 9 is a front elevational view of the testing apparatus in the open configuration;
FIG. 10 is a left side elevational view of the testing apparatus in the open configuration;
FIG. 11 is a rear elevational view of the testing apparatus in the open configuration;
FIG. 12 is a top plan view of the testing apparatus in the open configuration;
FIG. 13 is a bottom plan view of the testing apparatus in the open configuration; and,
FIG. 14 is another perspective view of the testing apparatus in the open configuration, and further includes environmental structure illustrated in broken lines.
The broken lines in the drawing views are included for the purpose of illustrating portions of the testing apparatus that form no part of the claimed design.

1 Claim, 14 Drawing Sheets



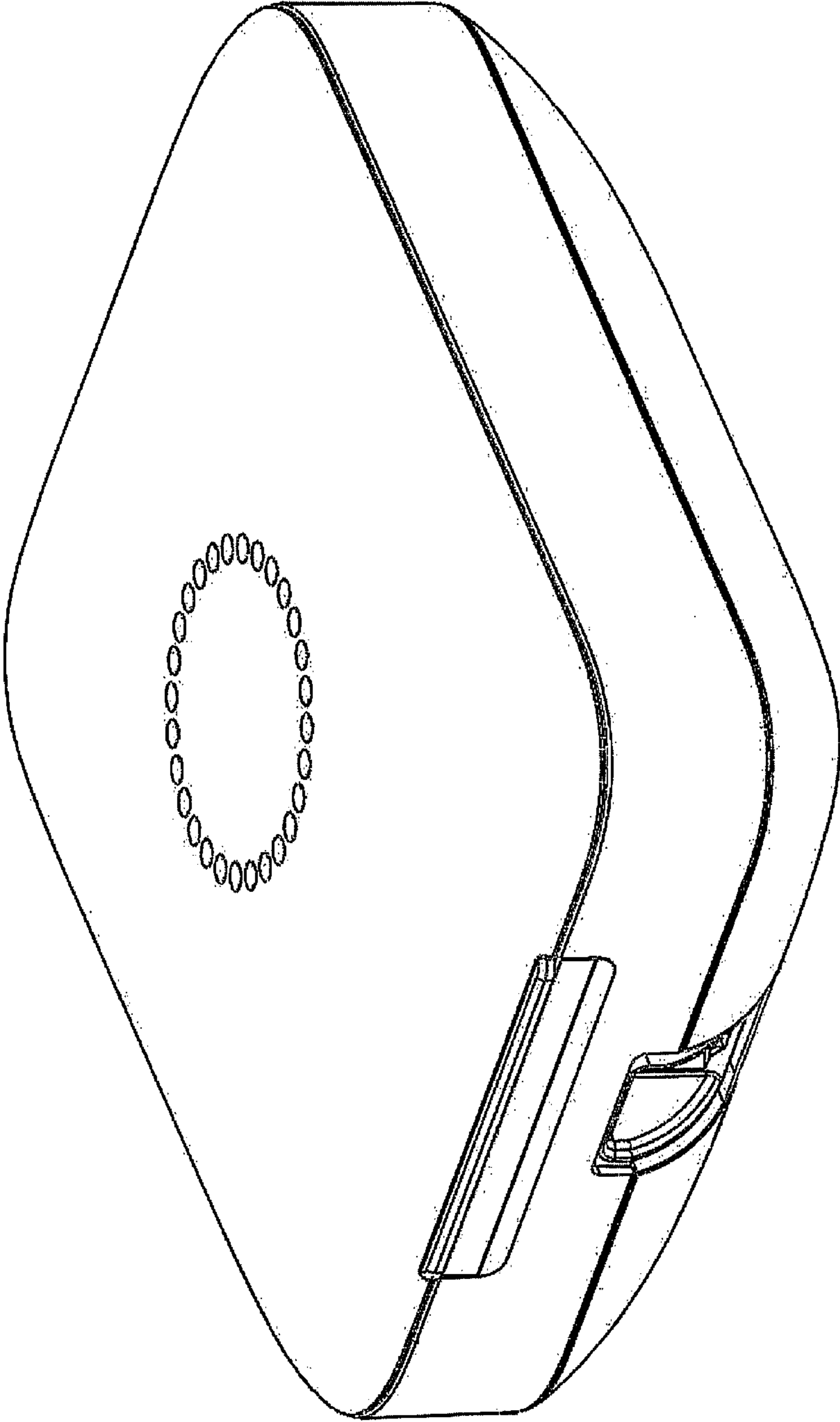


FIG. 1

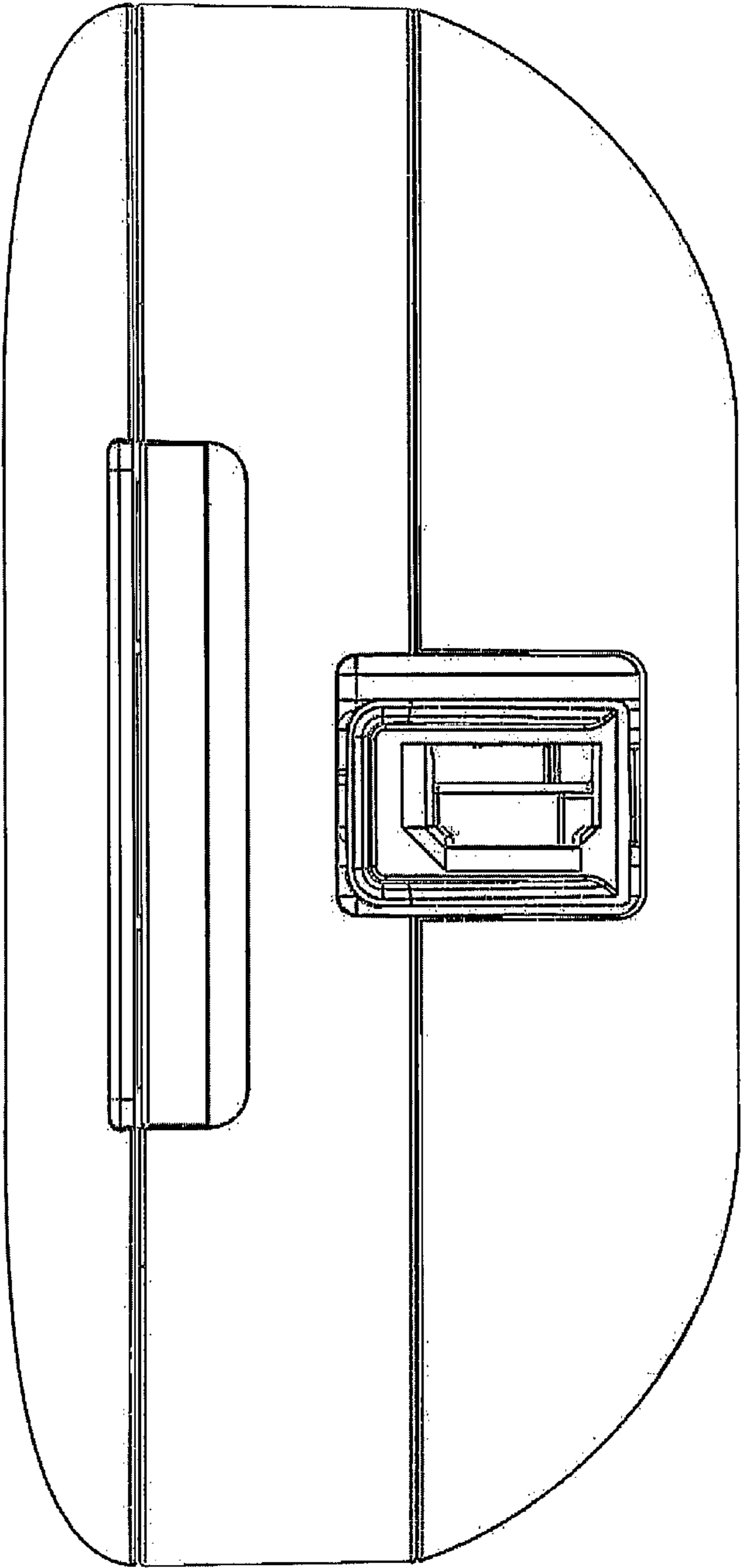


FIG. 2

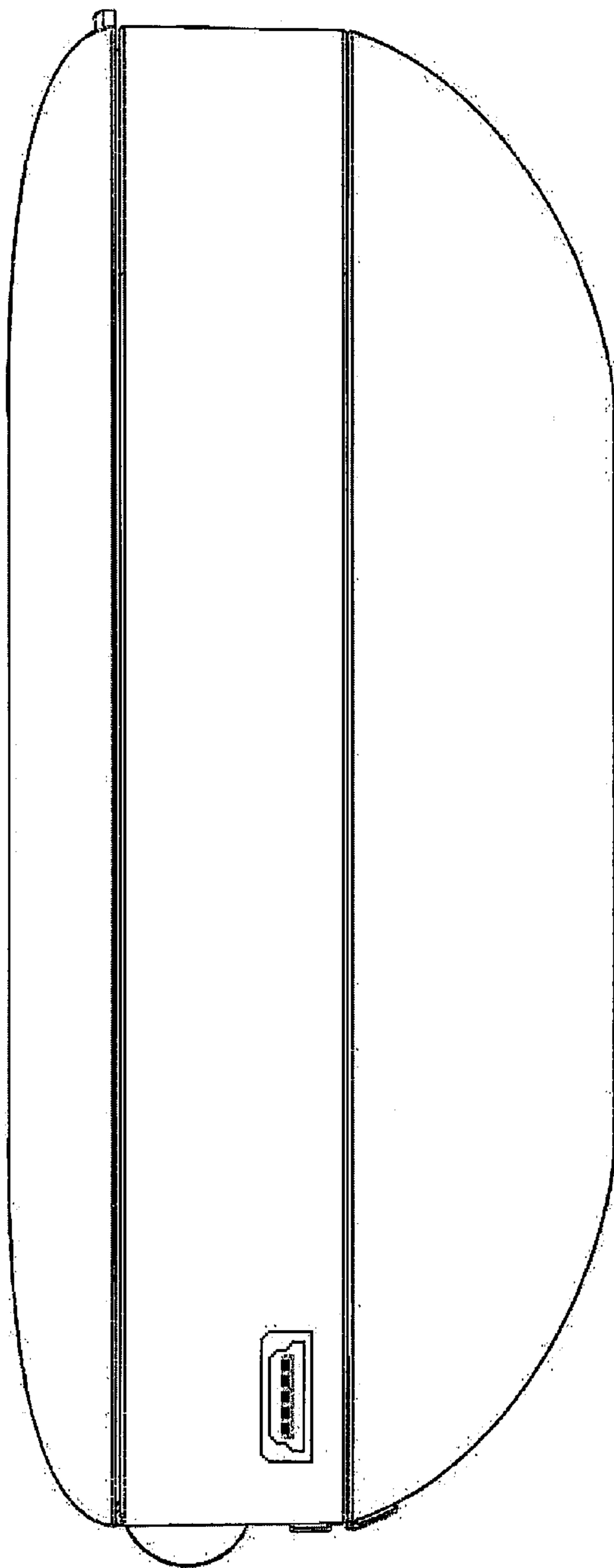


FIG. 3

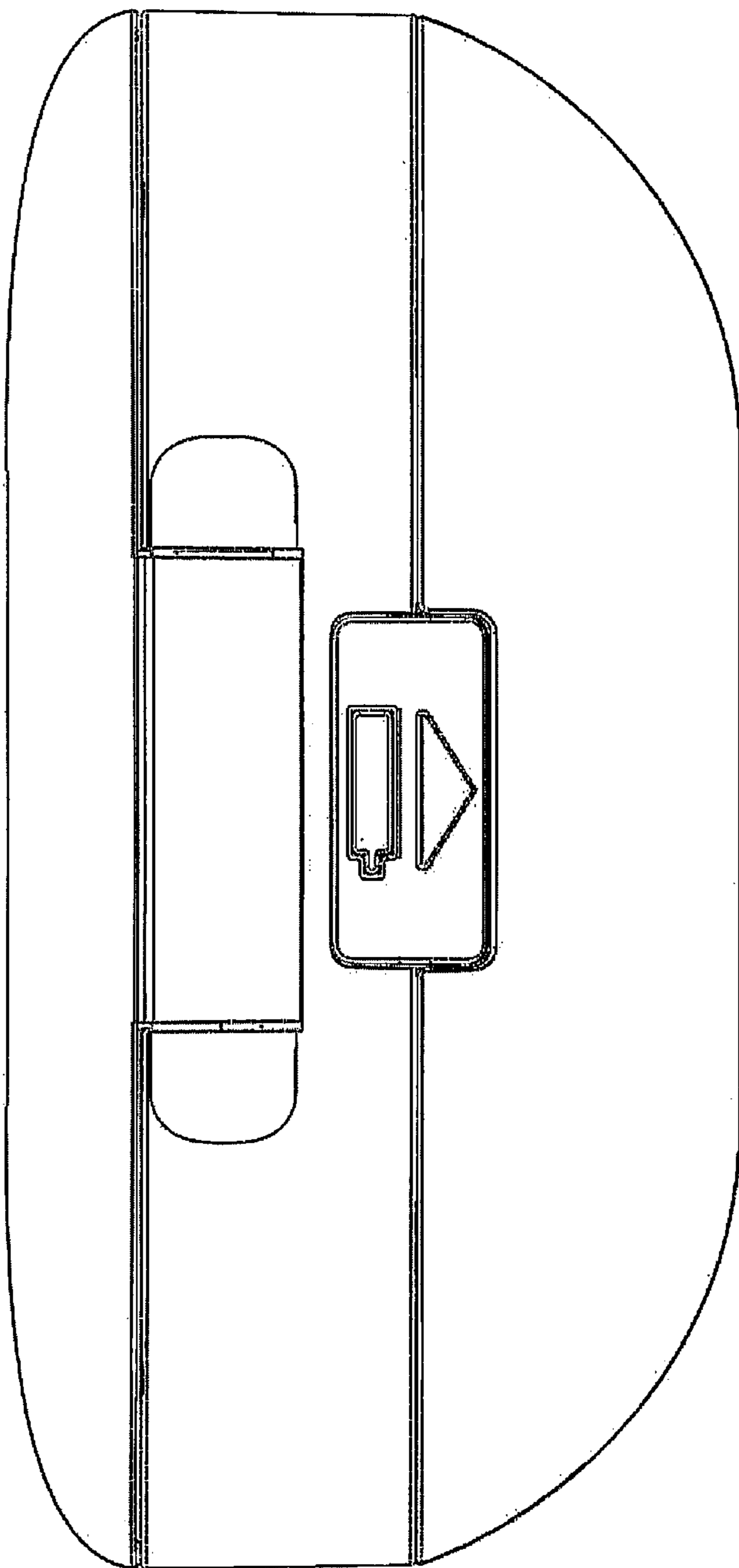


FIG. 4

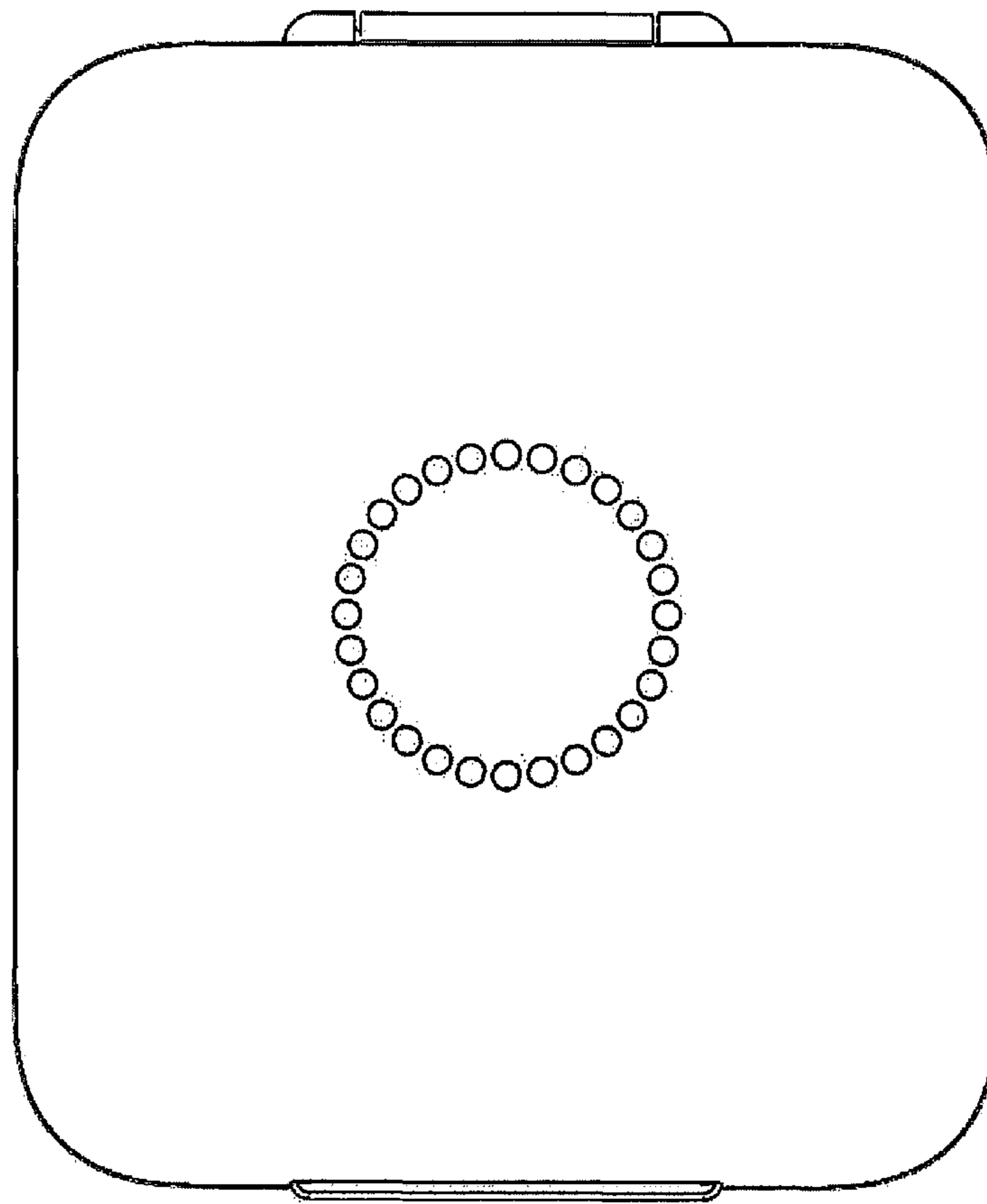


FIG. 5

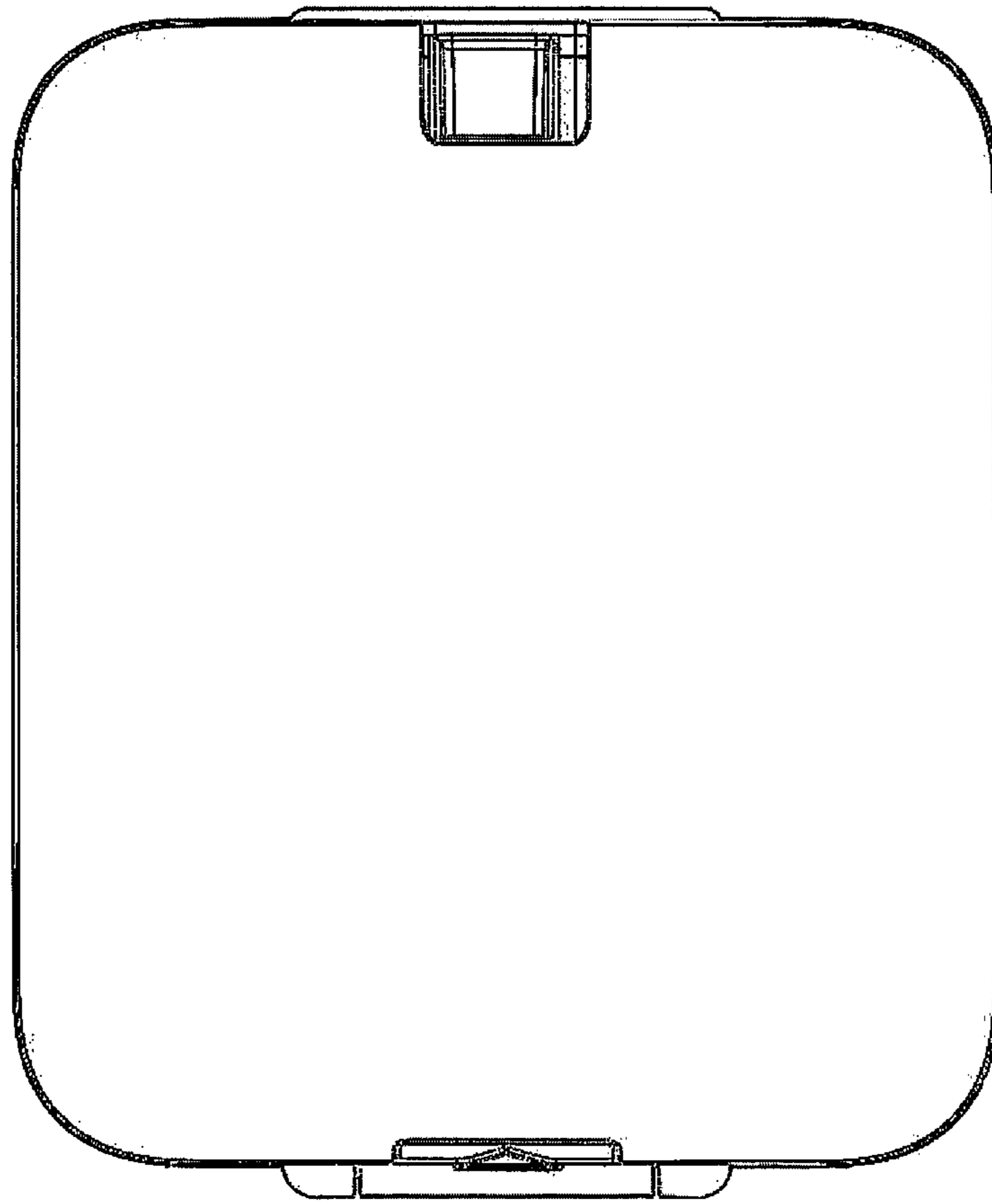


FIG. 6

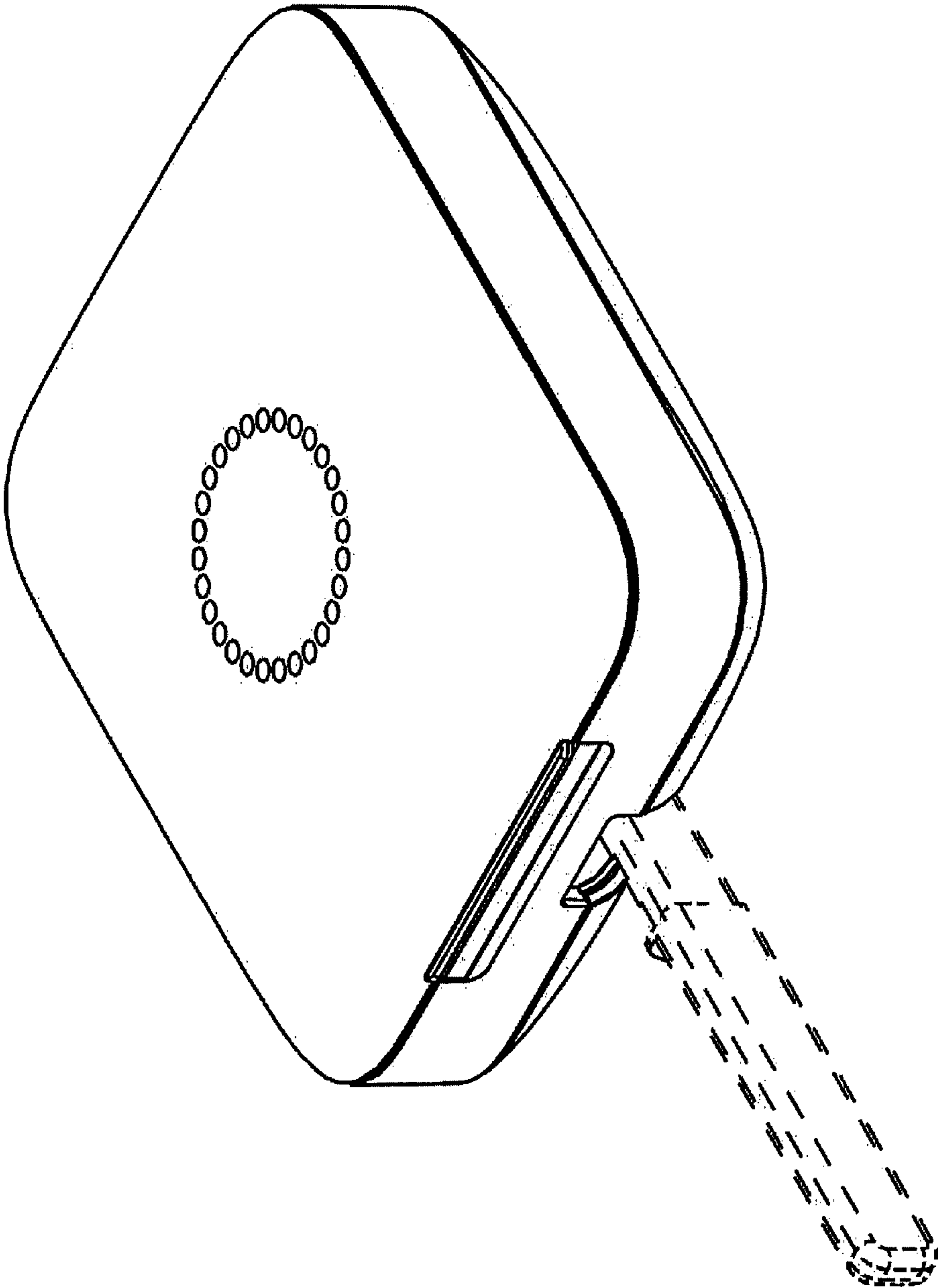


FIG. 7

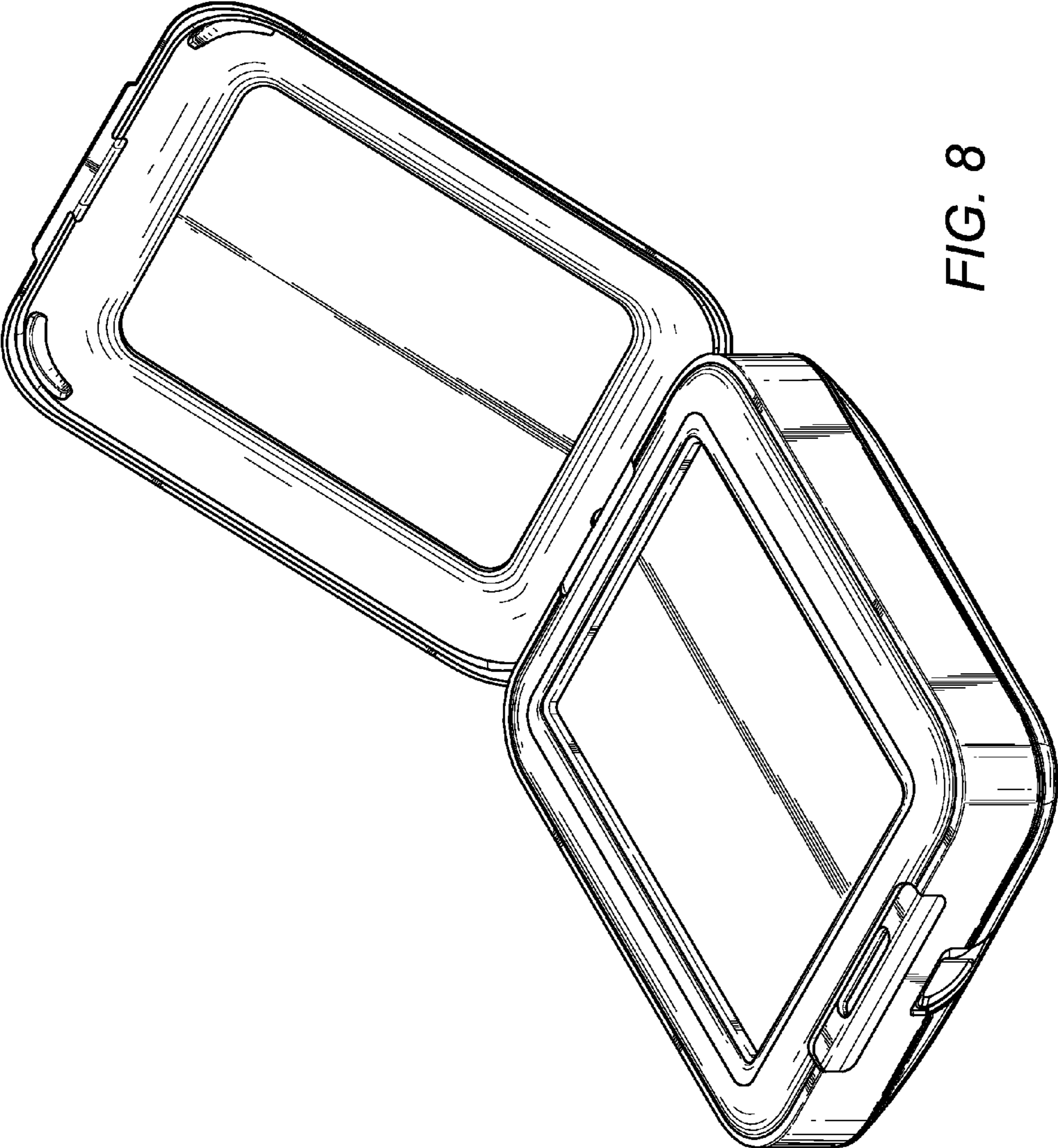


FIG. 8

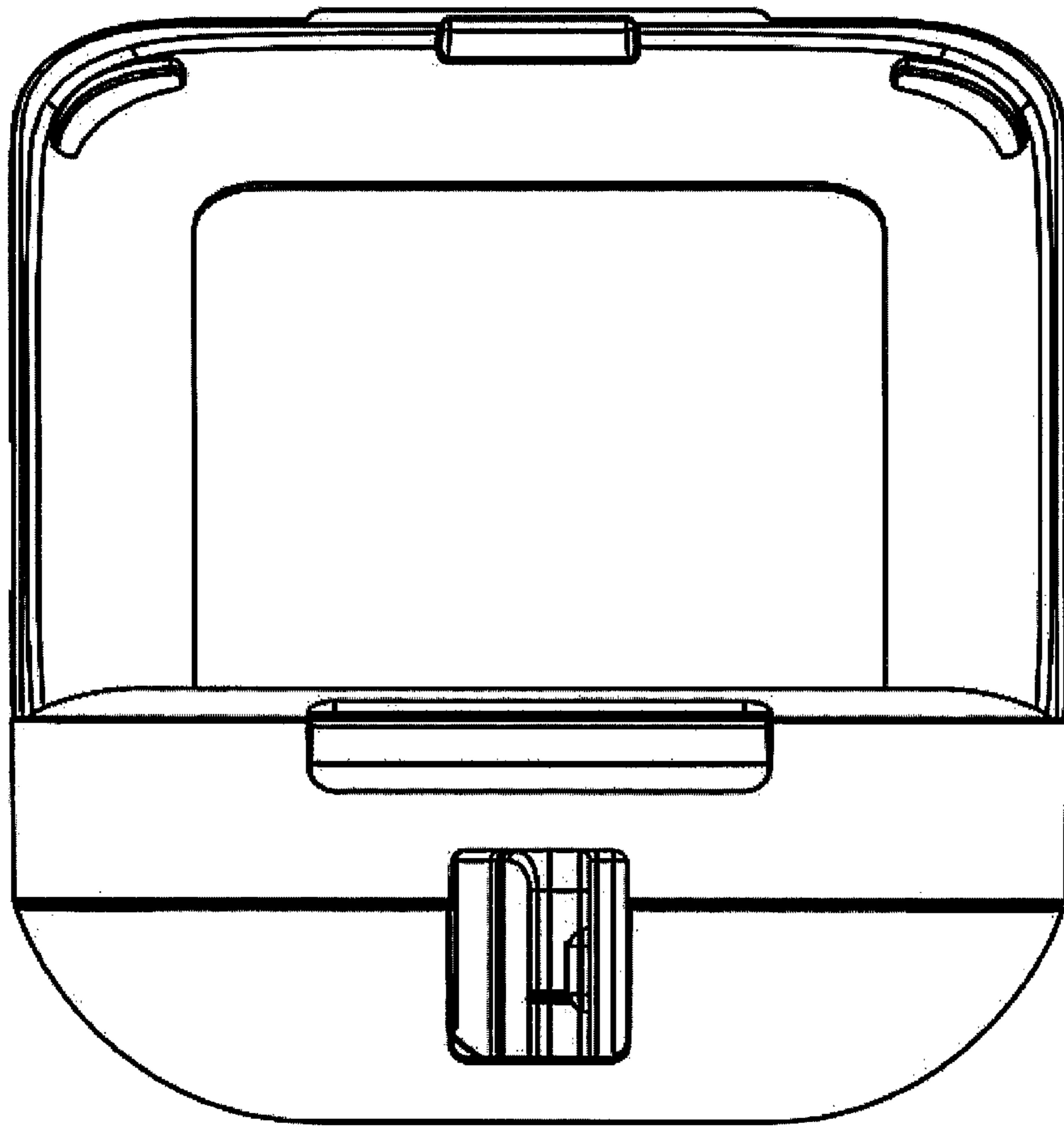


FIG. 9

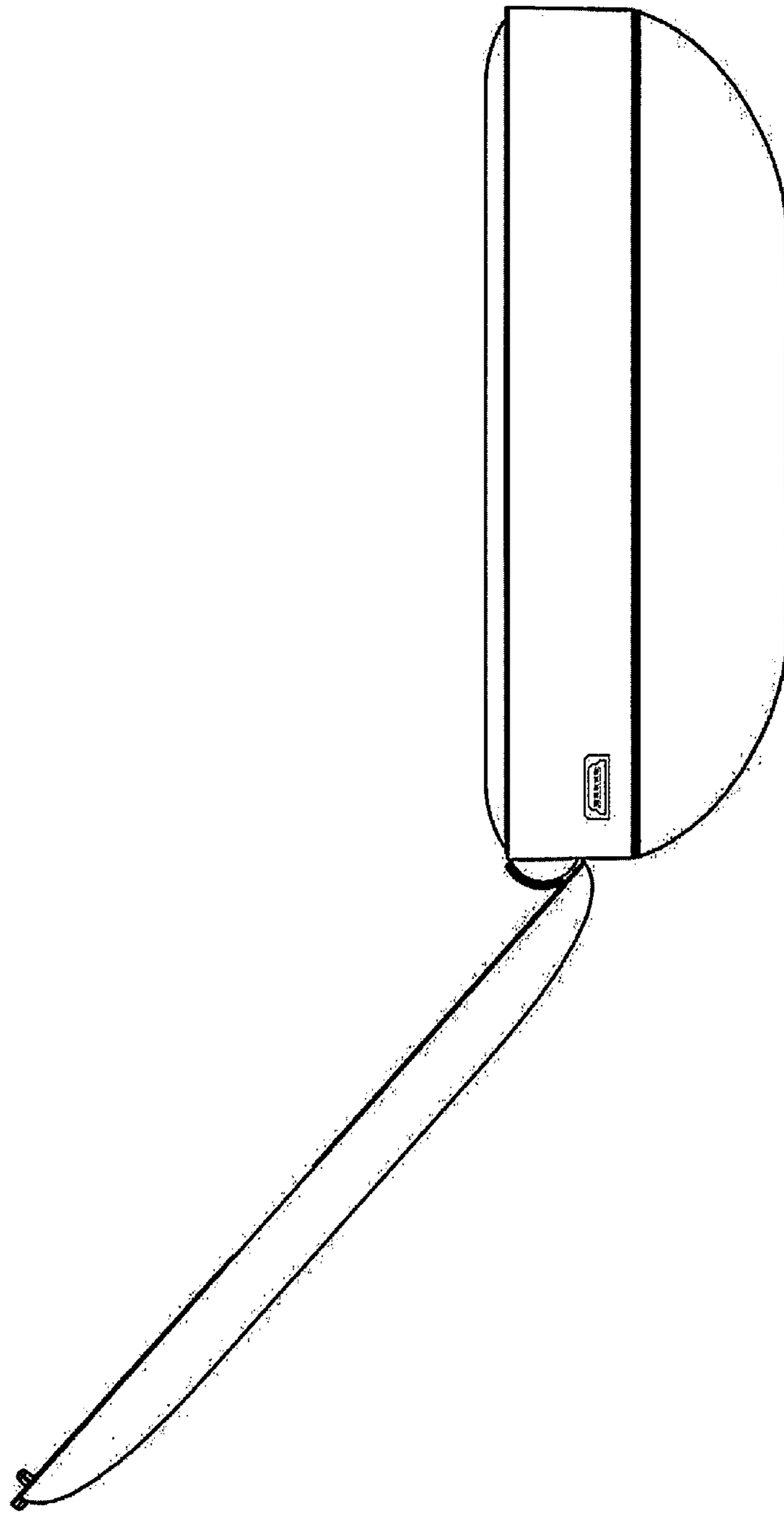


FIG. 10

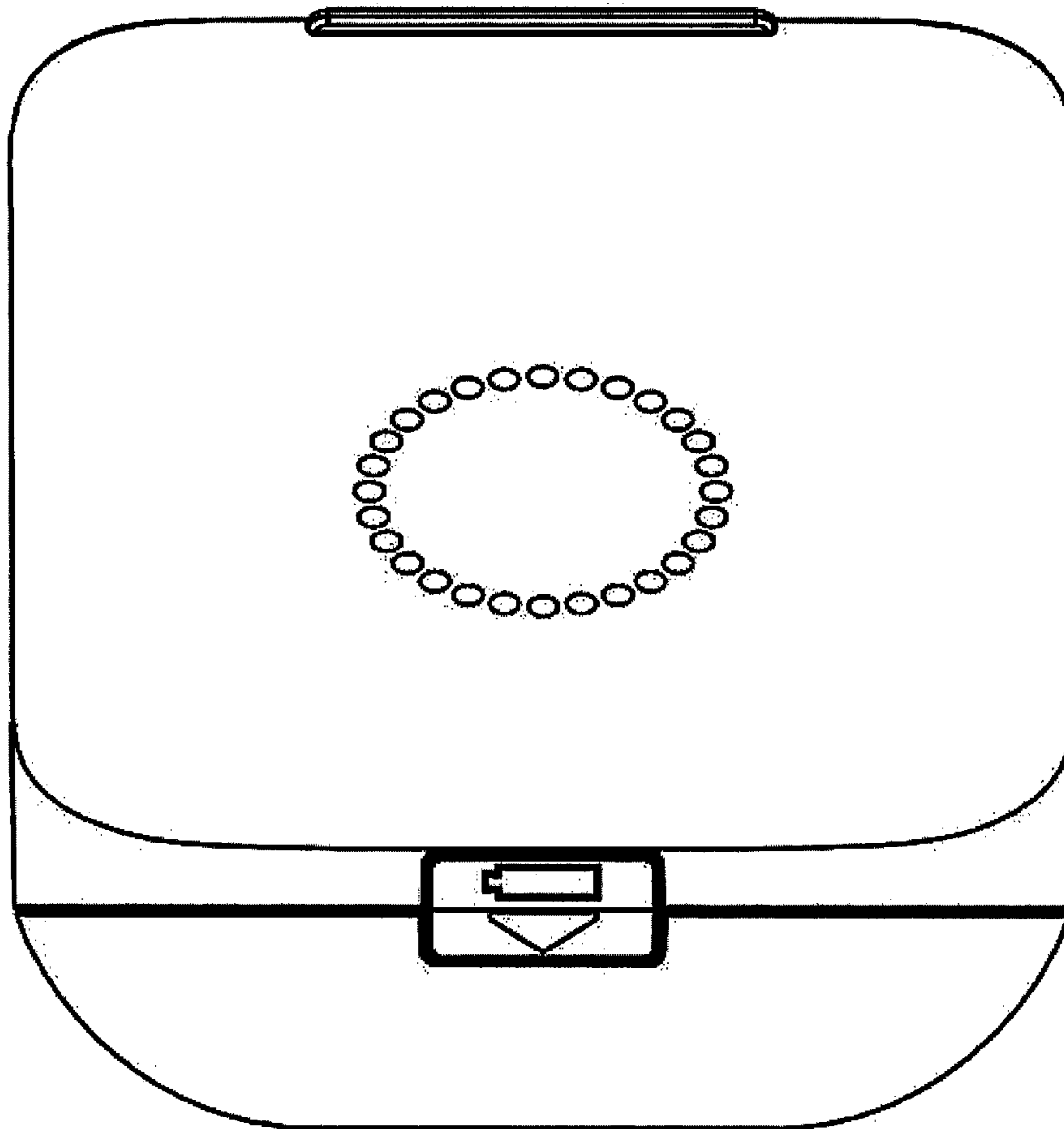


FIG. 11

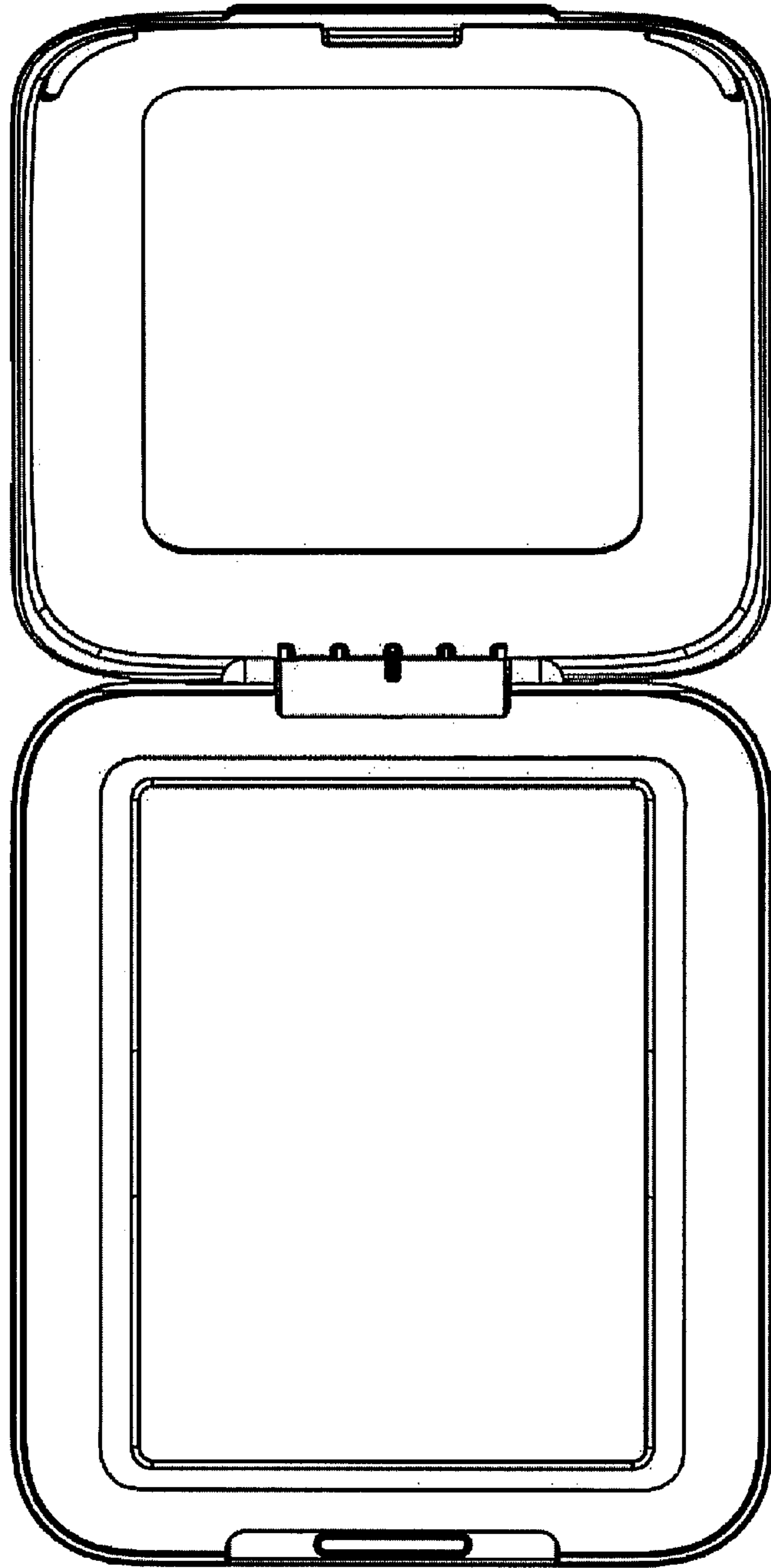


FIG. 12

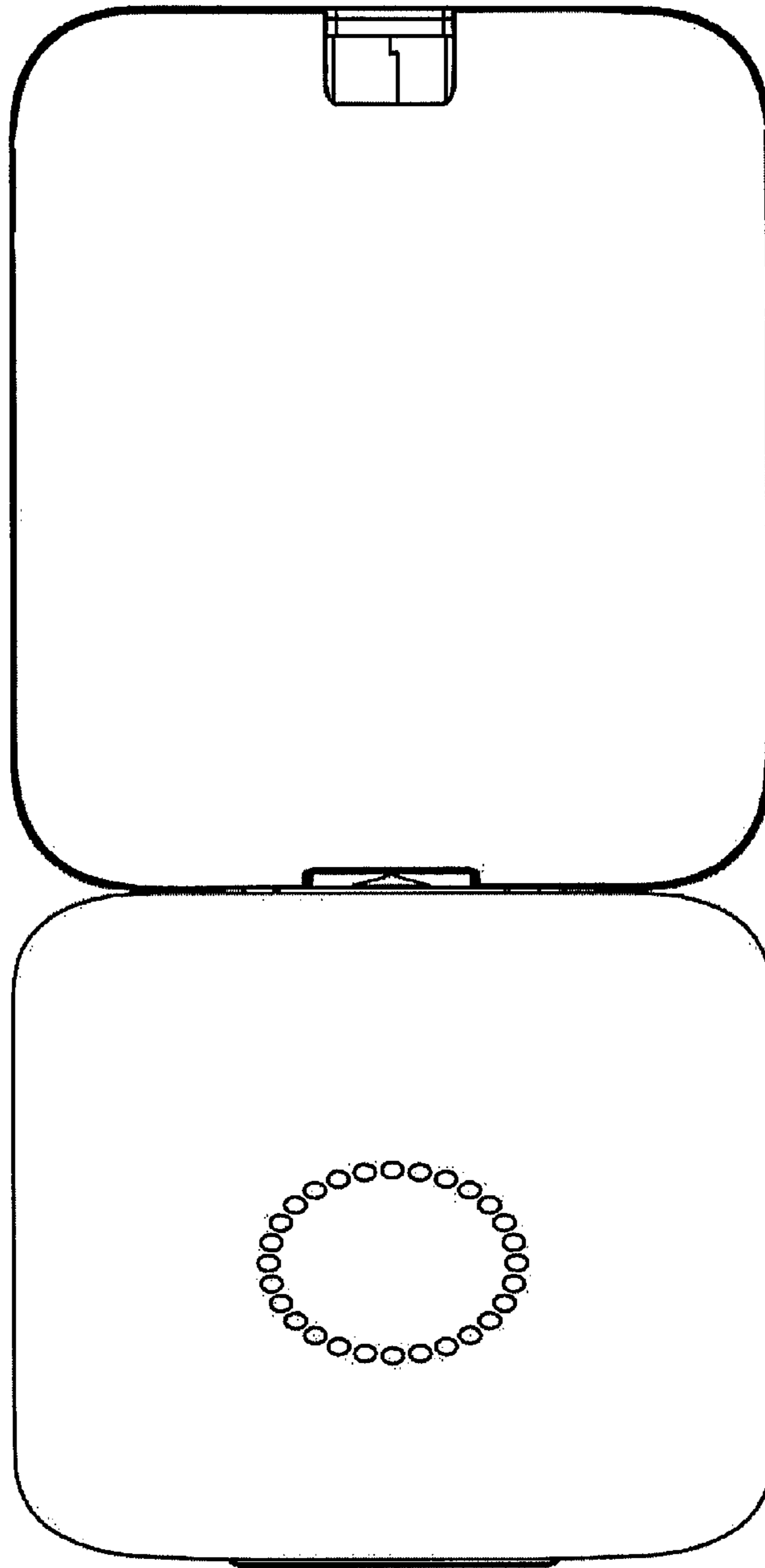


FIG. 13

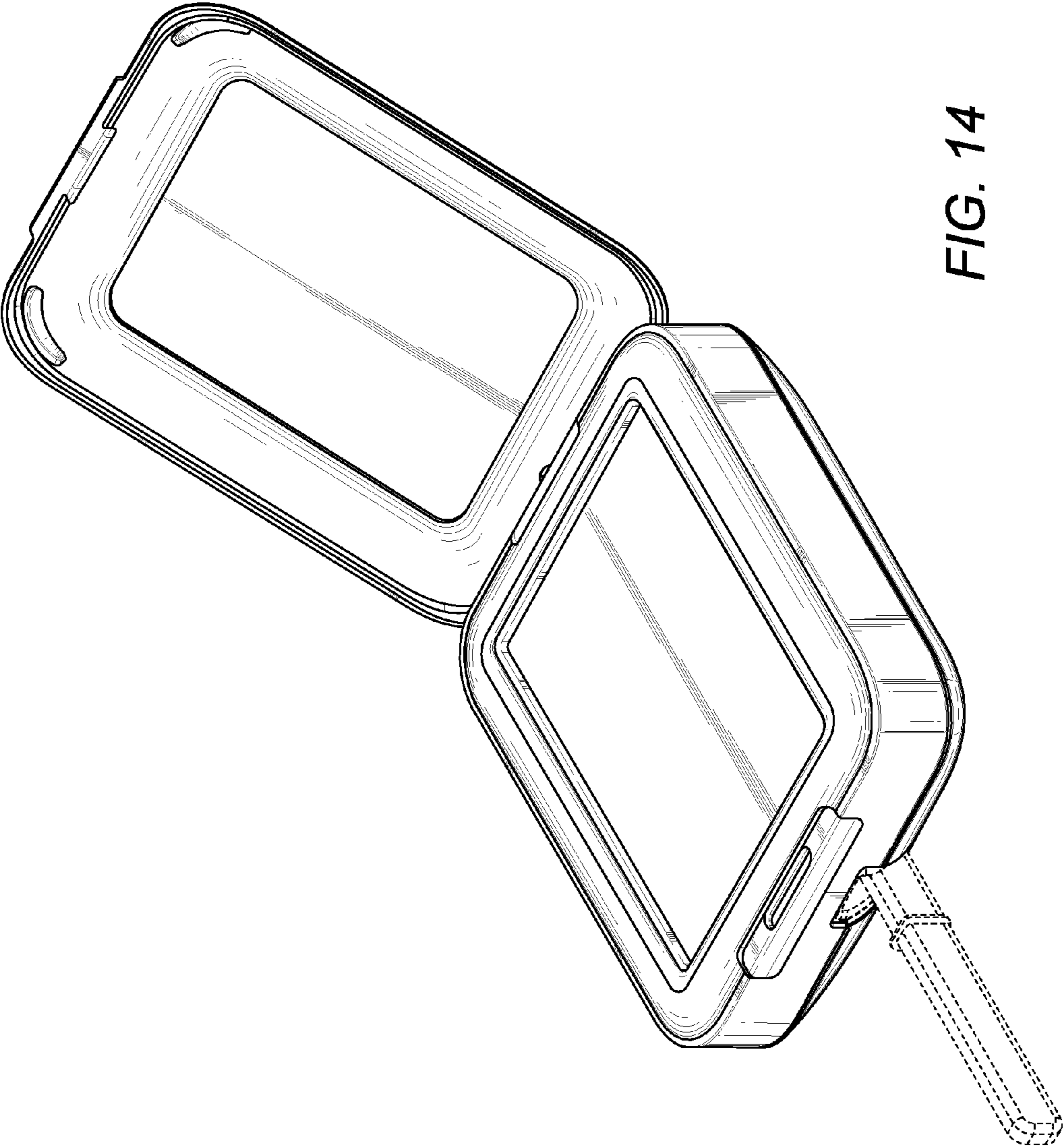


FIG. 14

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : D675,336 S
APPLICATION NO. : 29/389578
DATED : January 29, 2013
INVENTOR(S) : Laverack et al.

Page 1 of 16

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Please delete the title page and insert the title page showing an illustrative figure as attached.

In the Drawings

Please delete drawing sheets 1-14 and insert drawing sheets 1-14 with figures 1-14 as attached.

Signed and Sealed this
Fourth Day of February, 2014



Michelle K. Lee
Deputy Director of the United States Patent and Trademark Office

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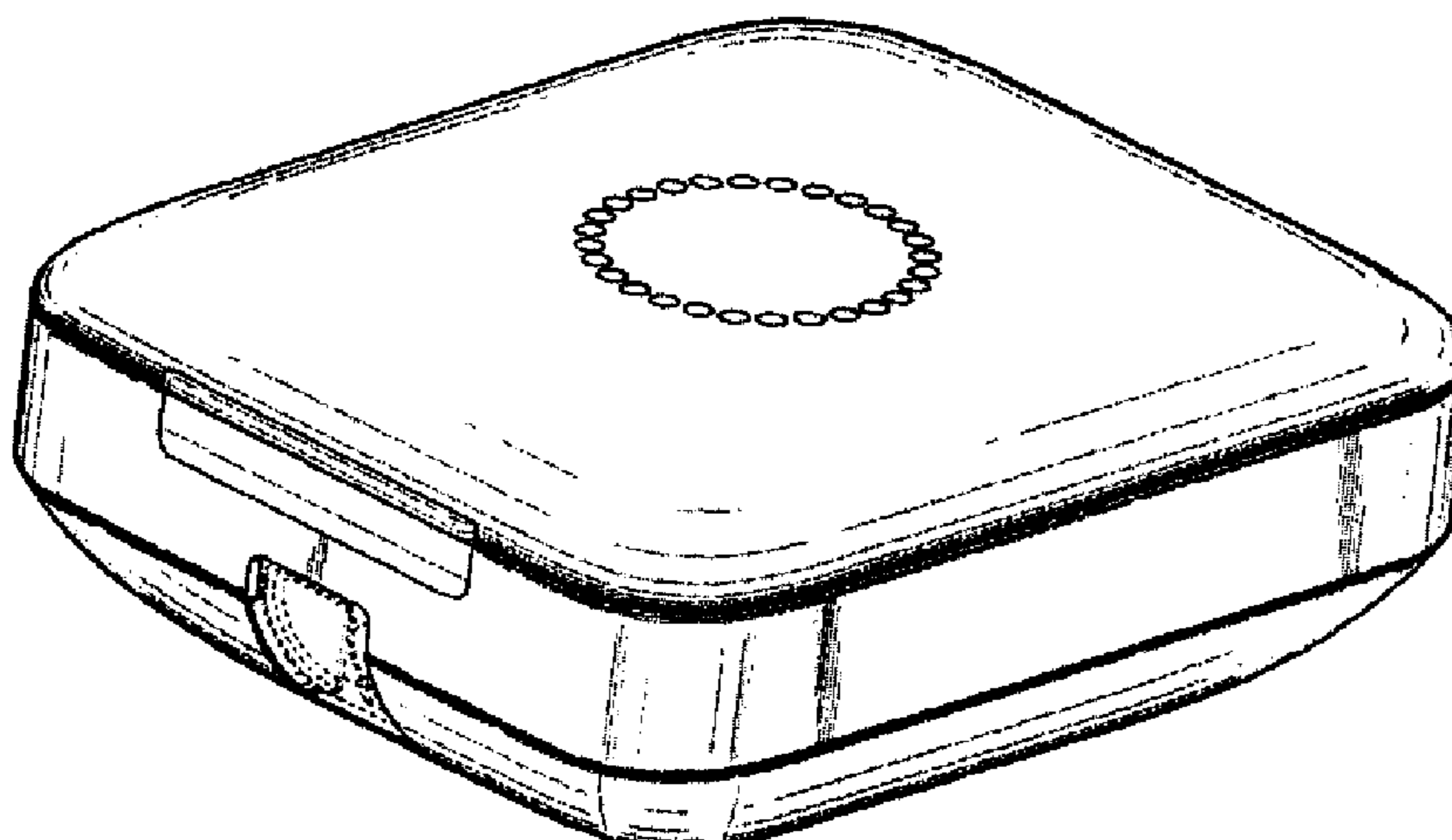
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Primary Examiner — Anhdao Doan

1 Claim, 14 Drawing Sheets



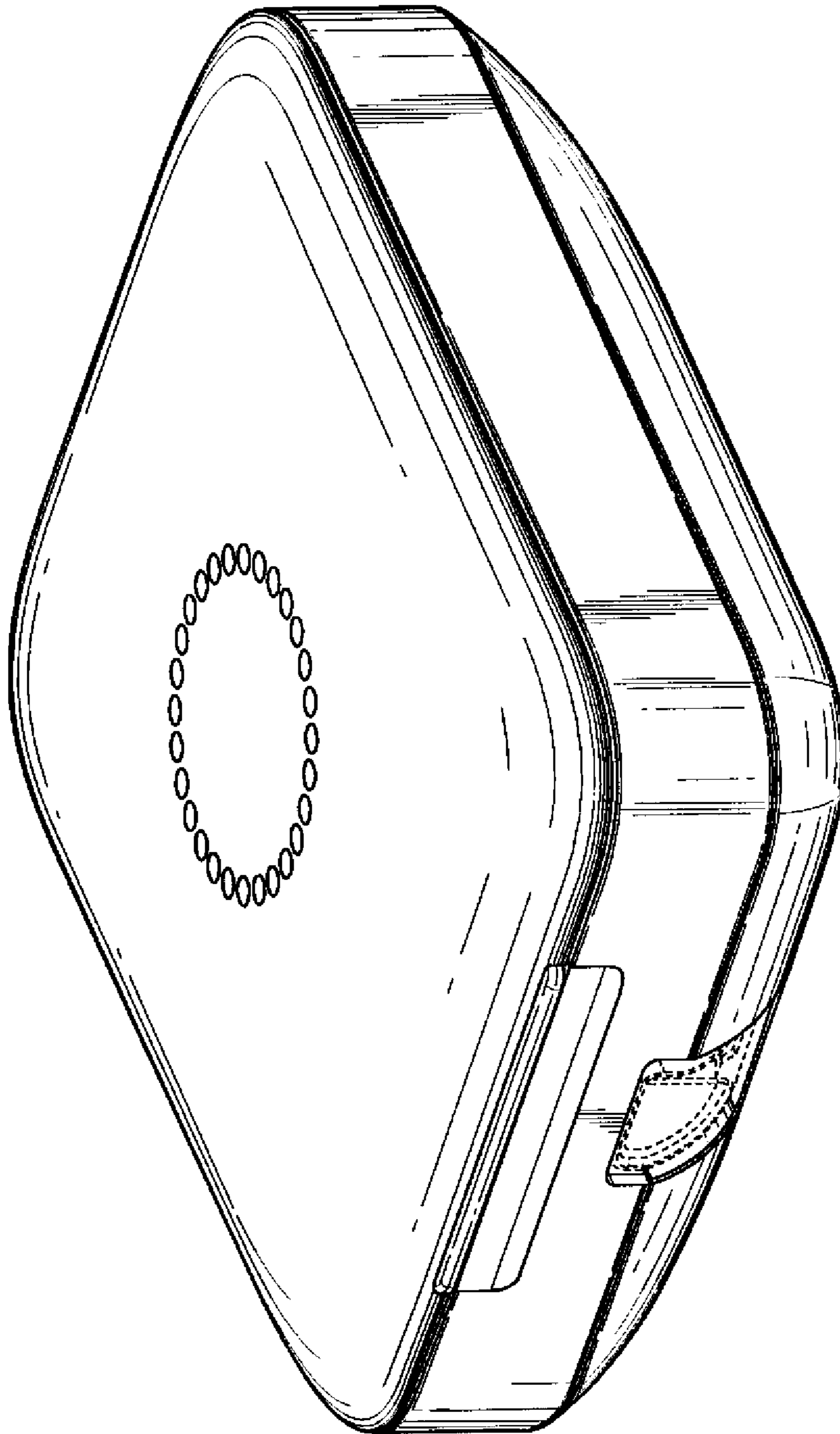


FIG. 1

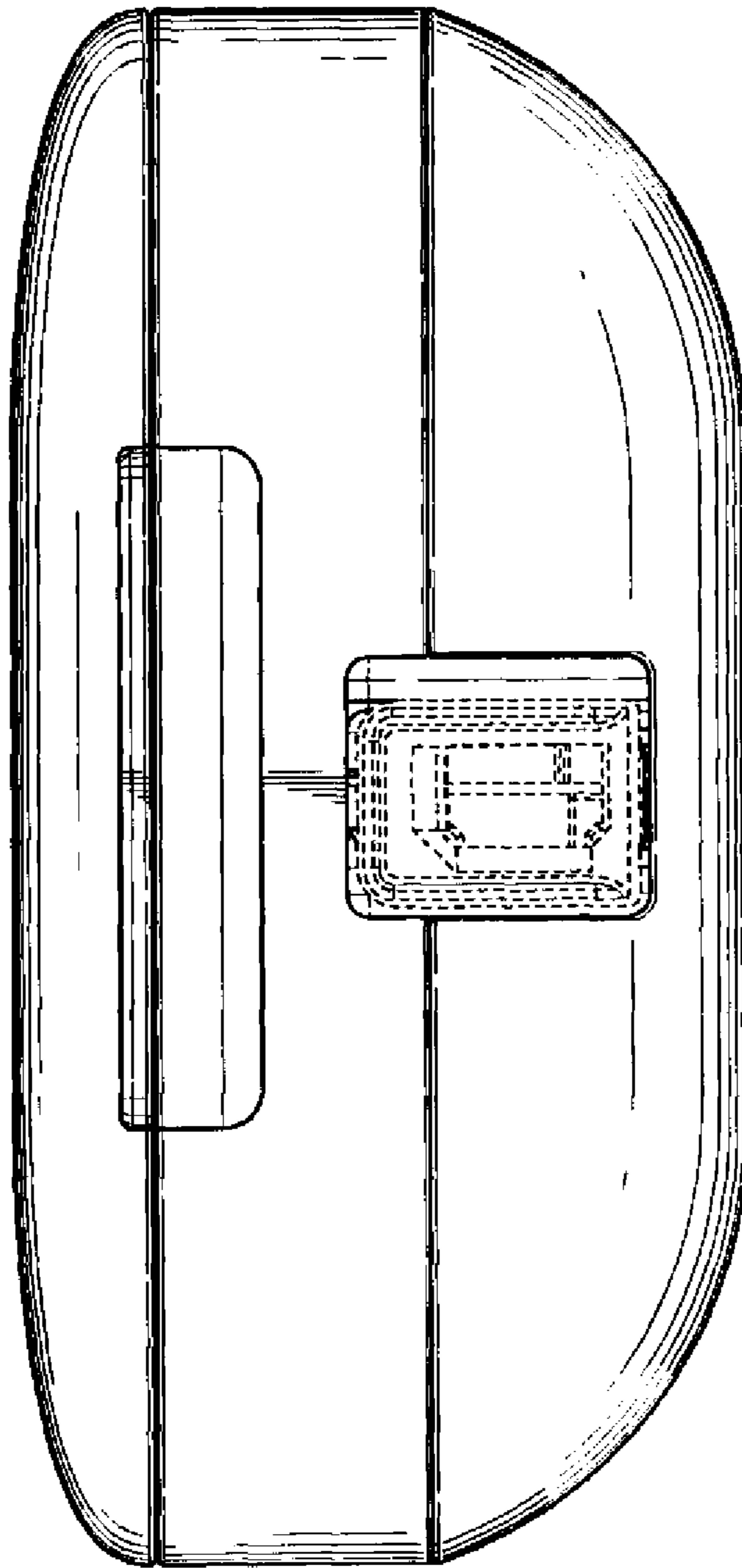


FIG. 2

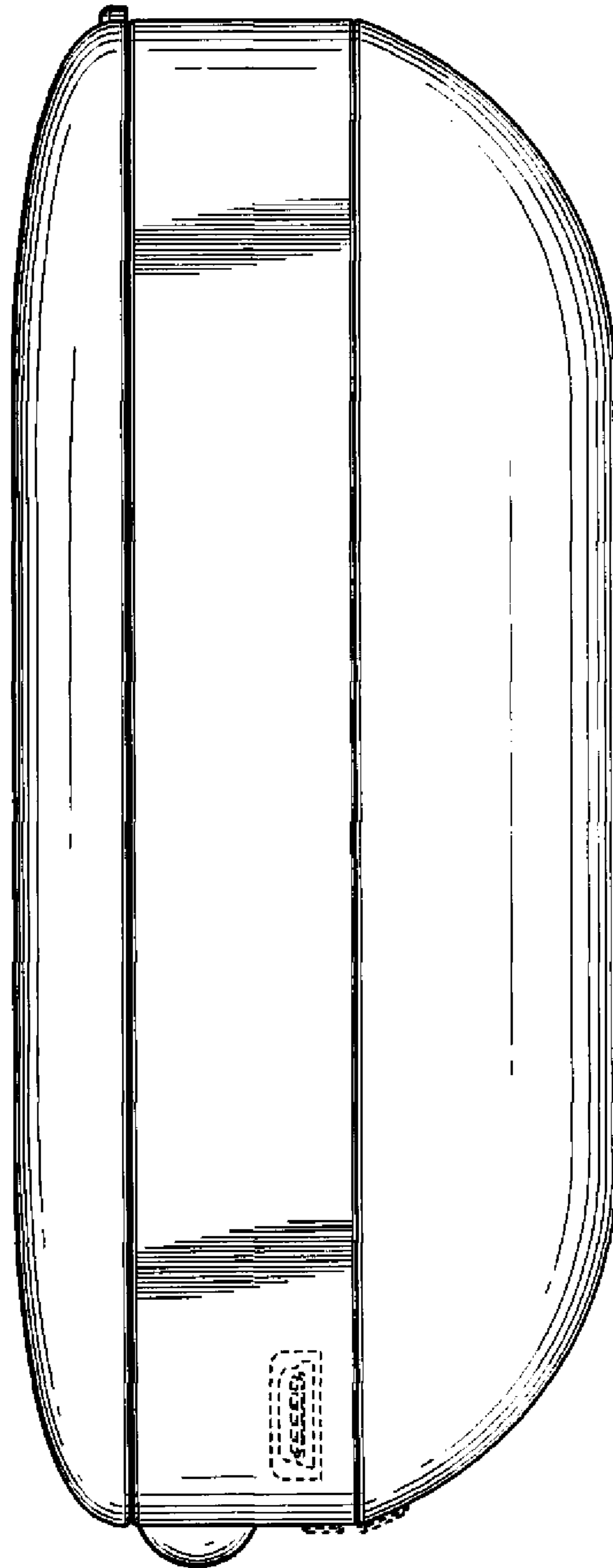


FIG. 3

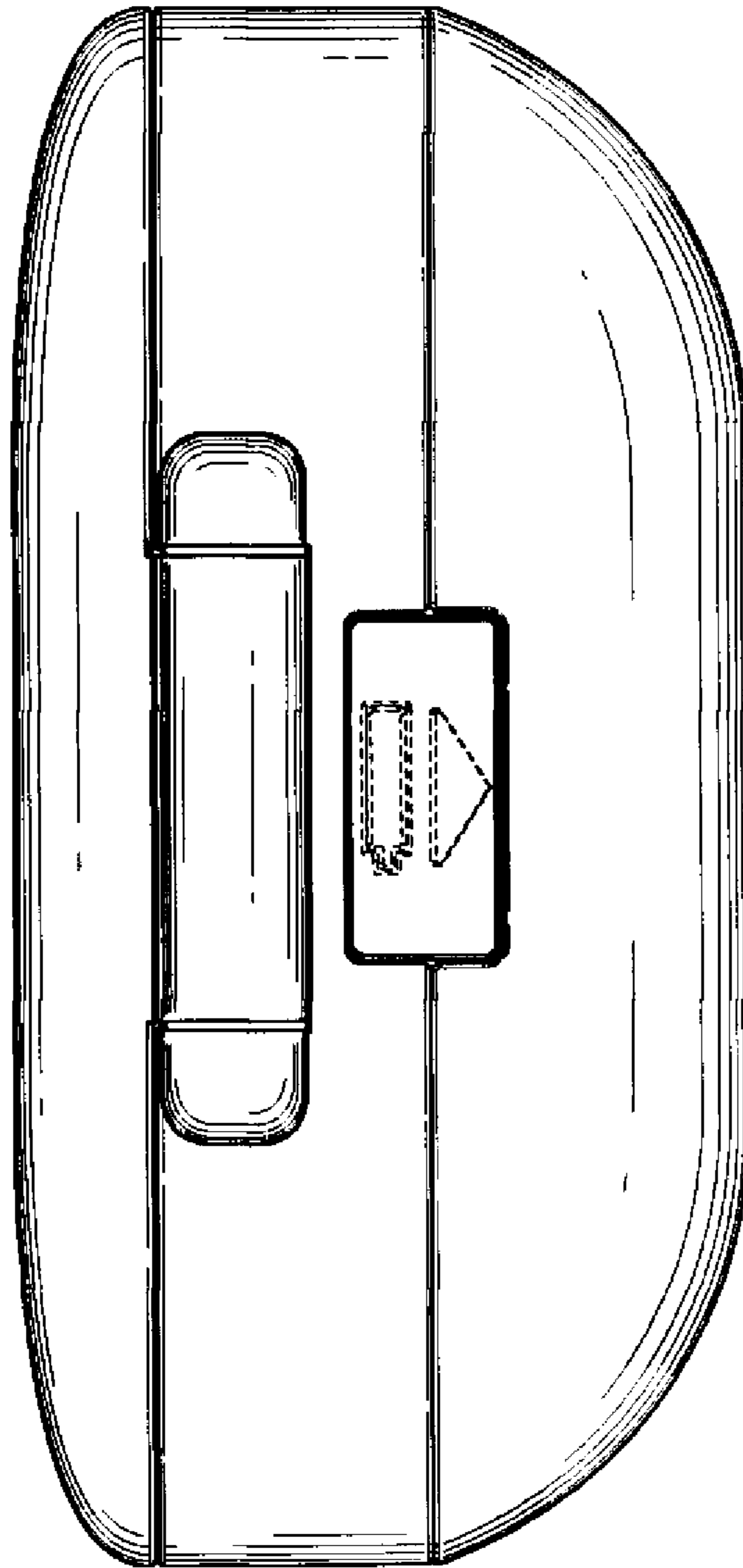


FIG. 4

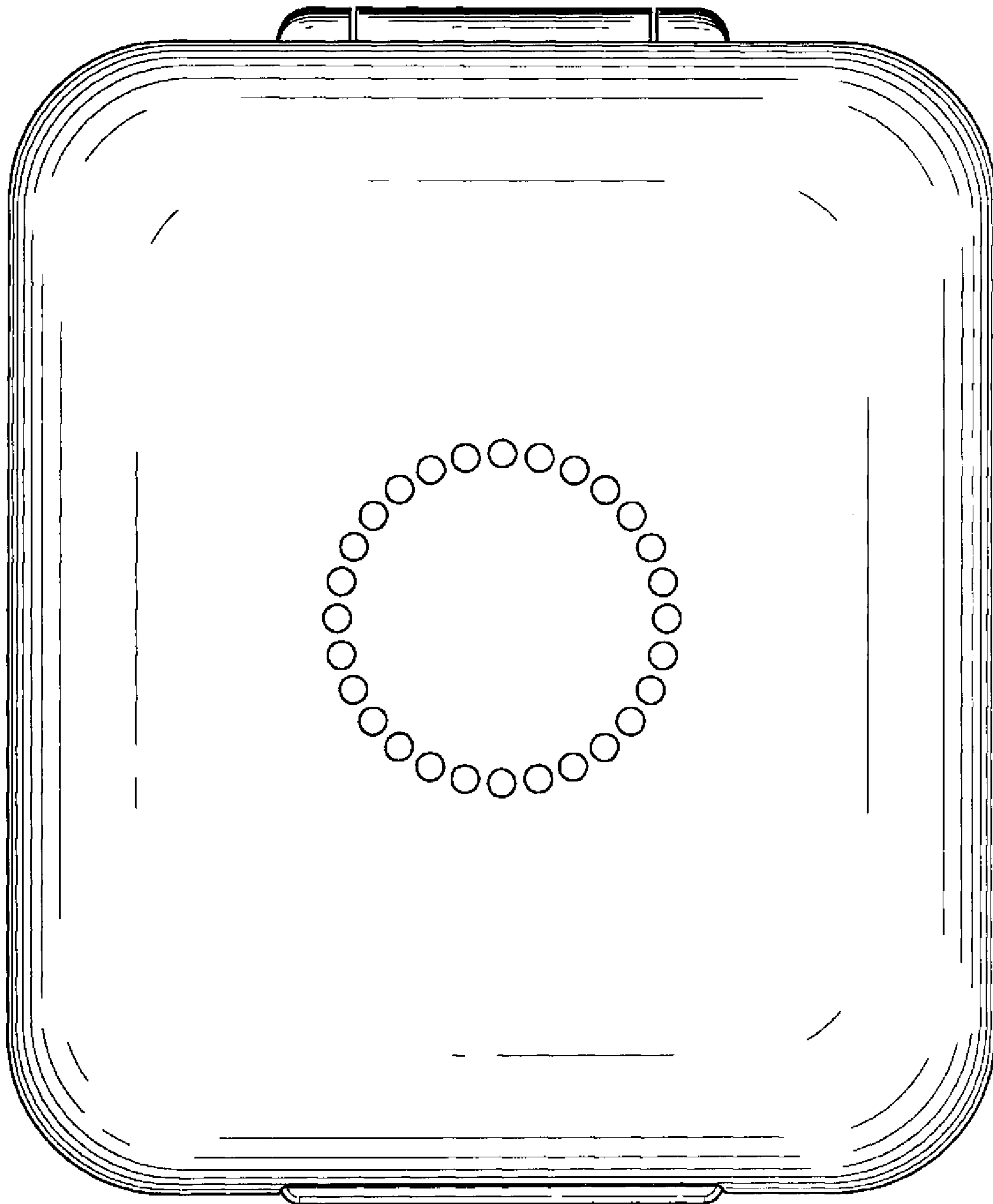


FIG. 5

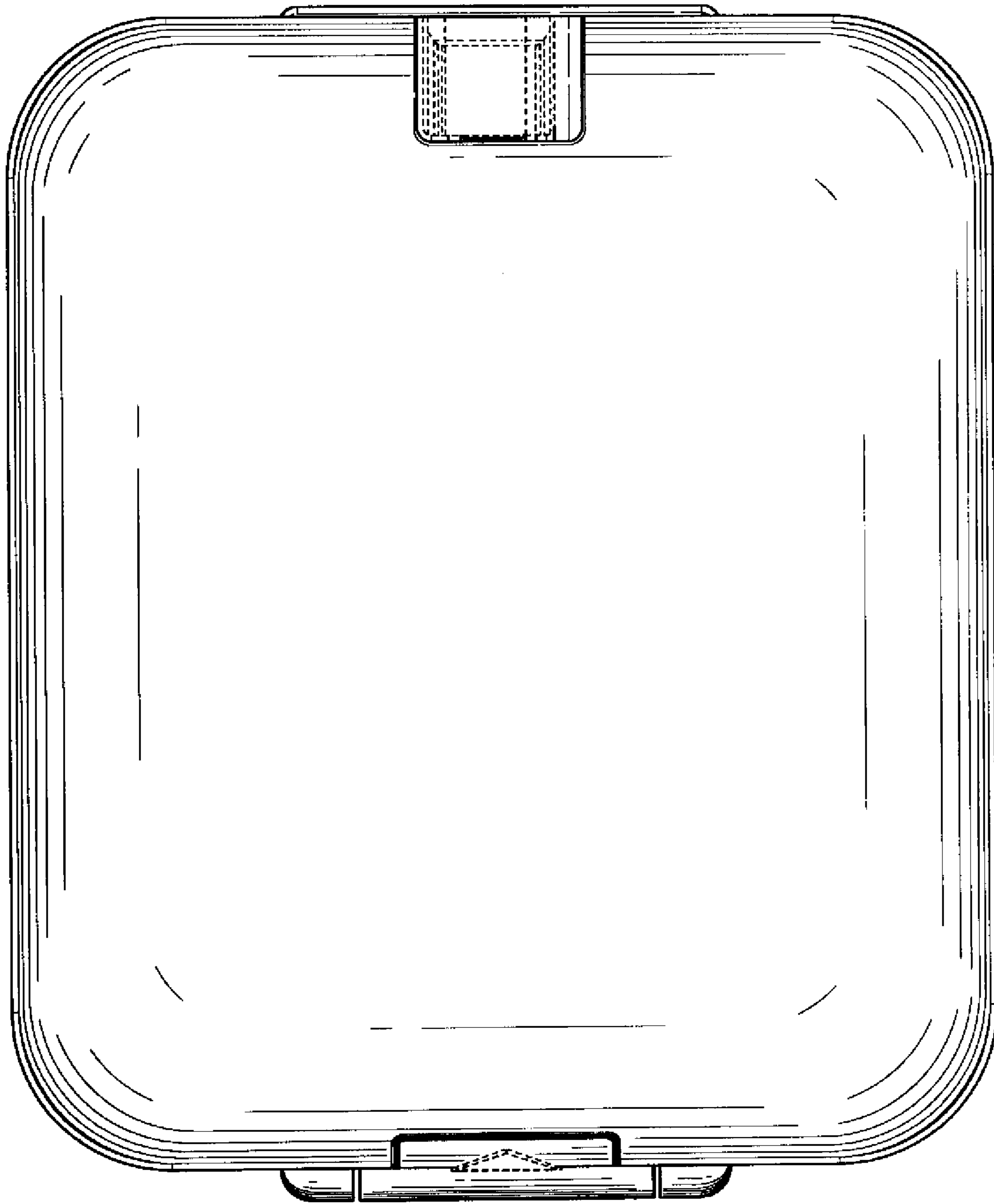


FIG. 6

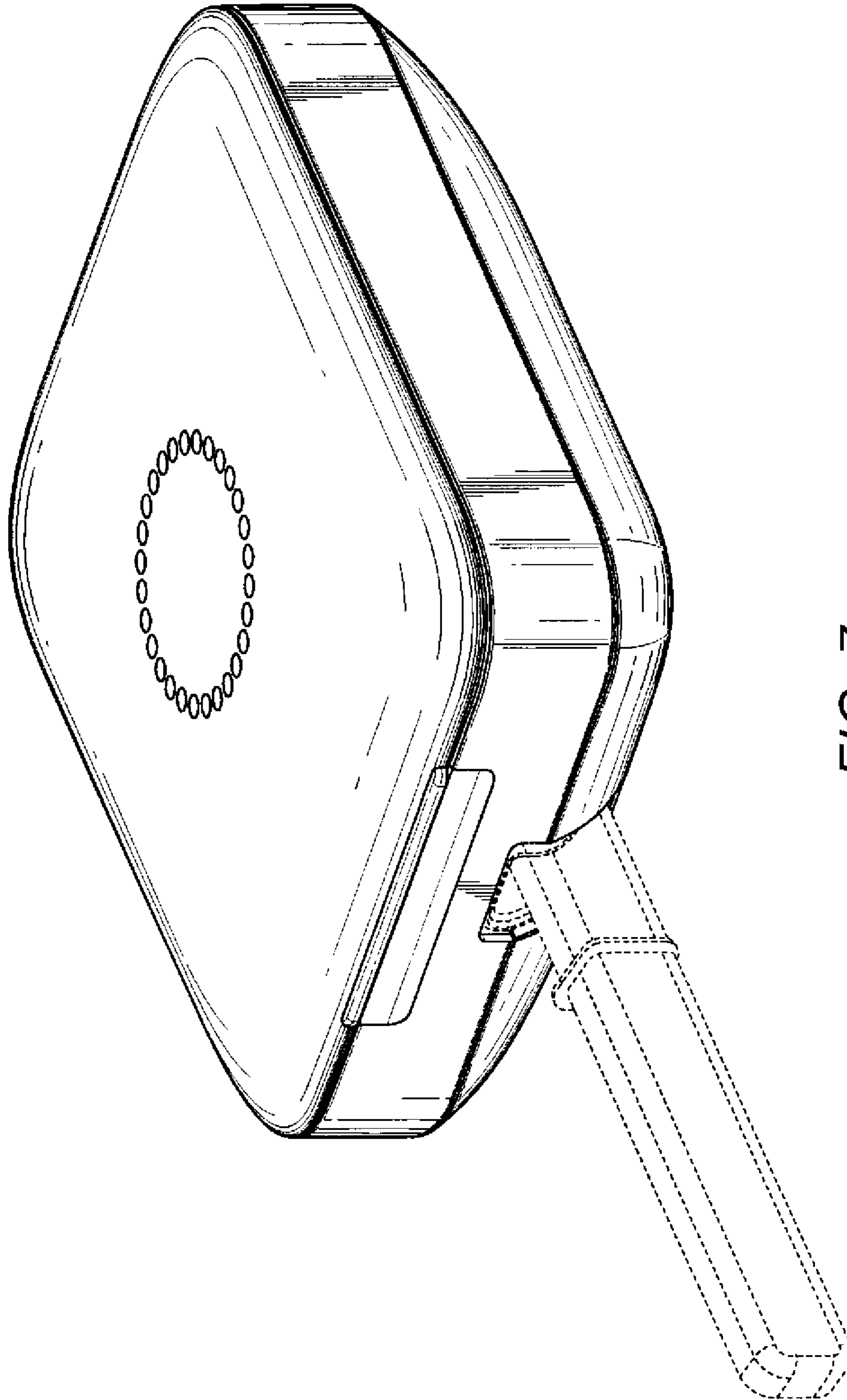


FIG. 7

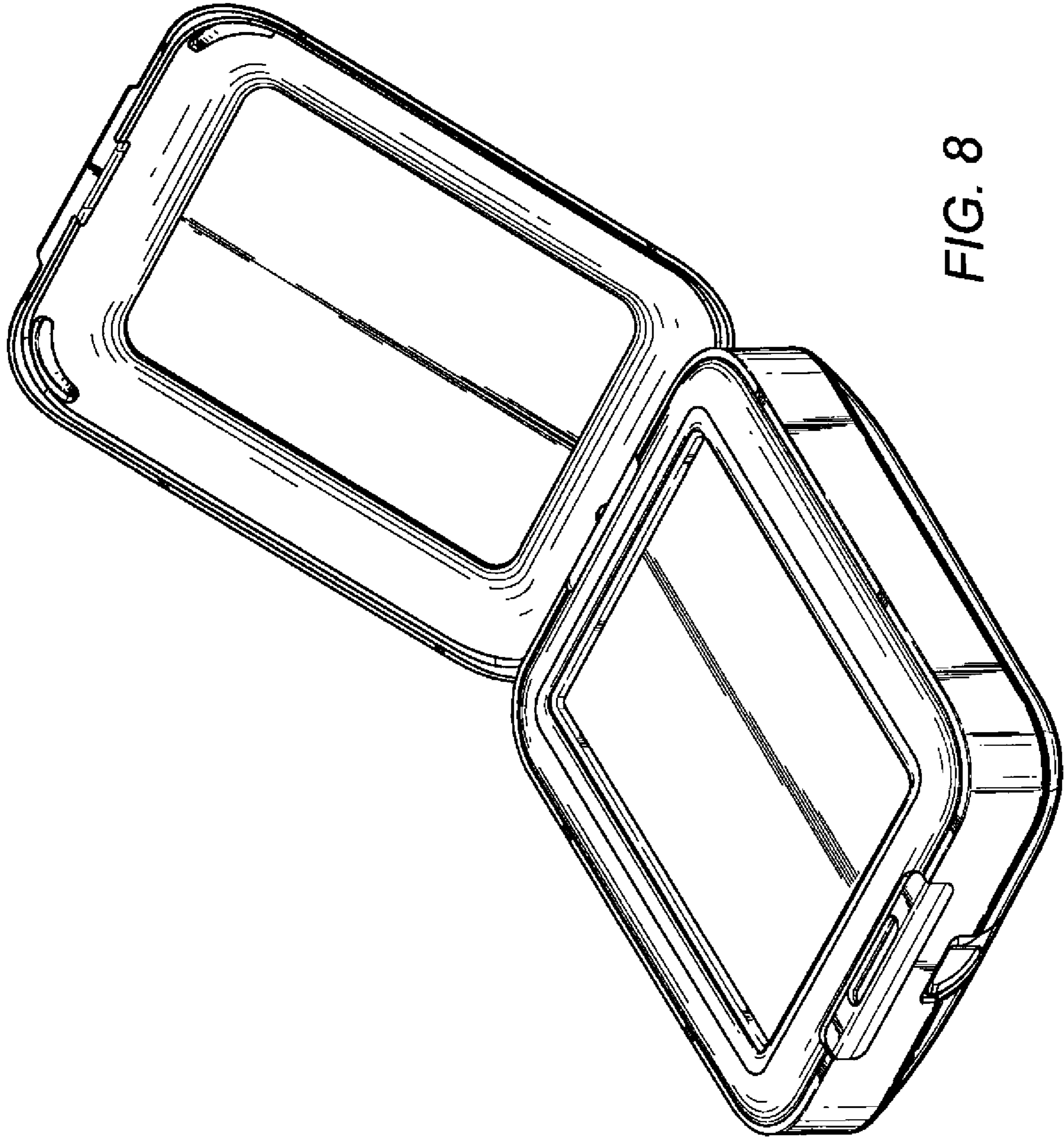


FIG. 8

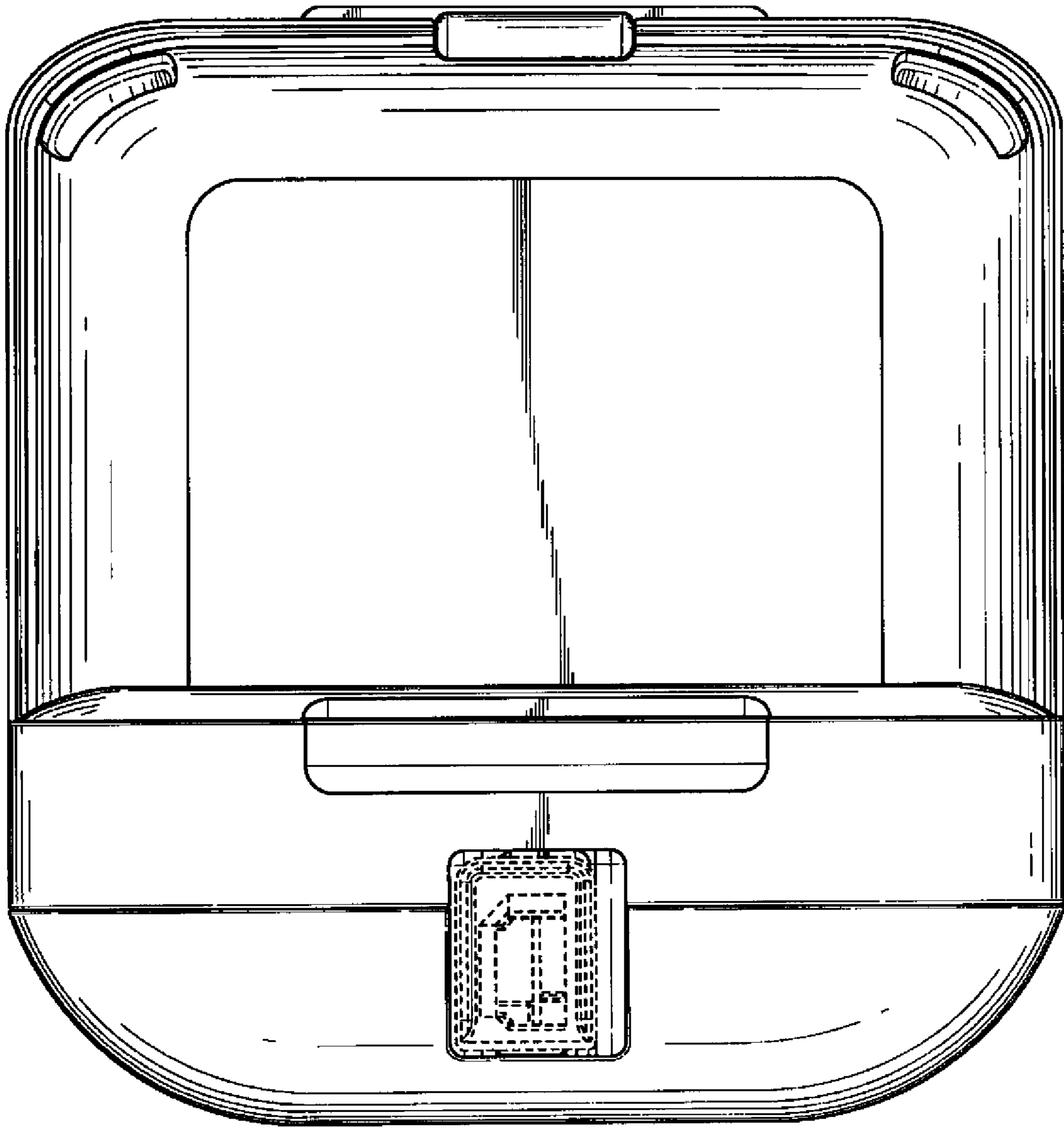


FIG. 9

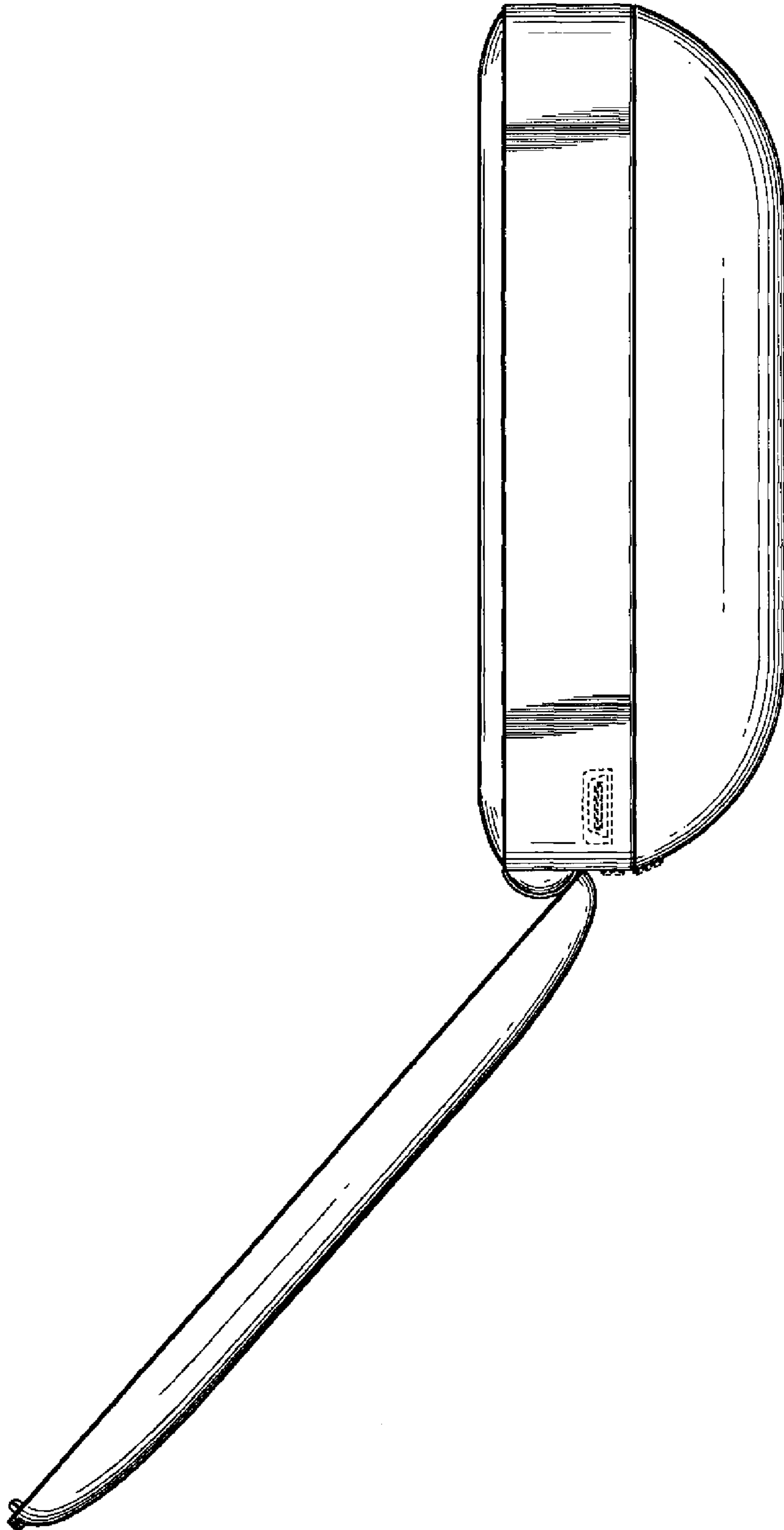


FIG. 10

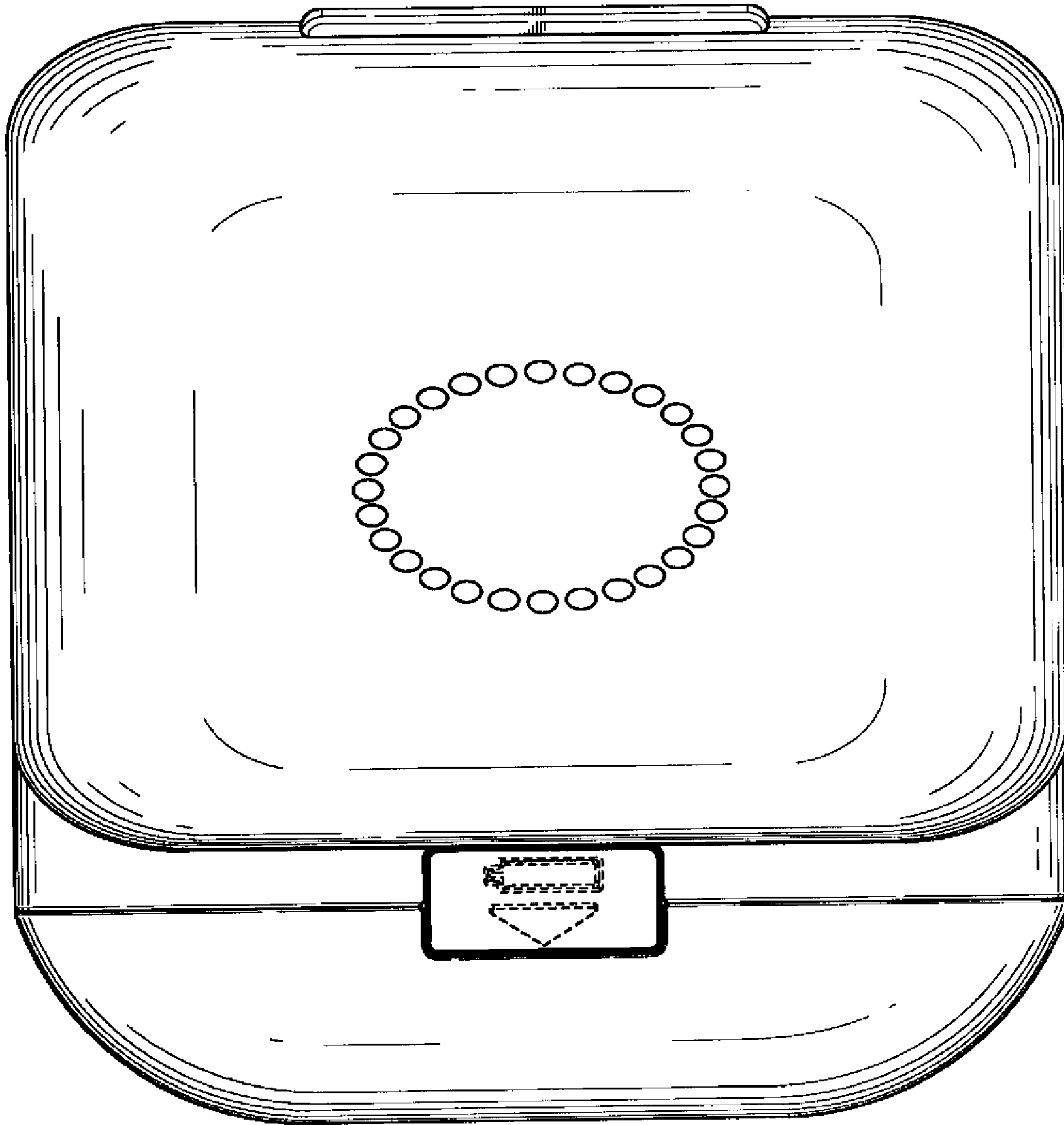


FIG. 11

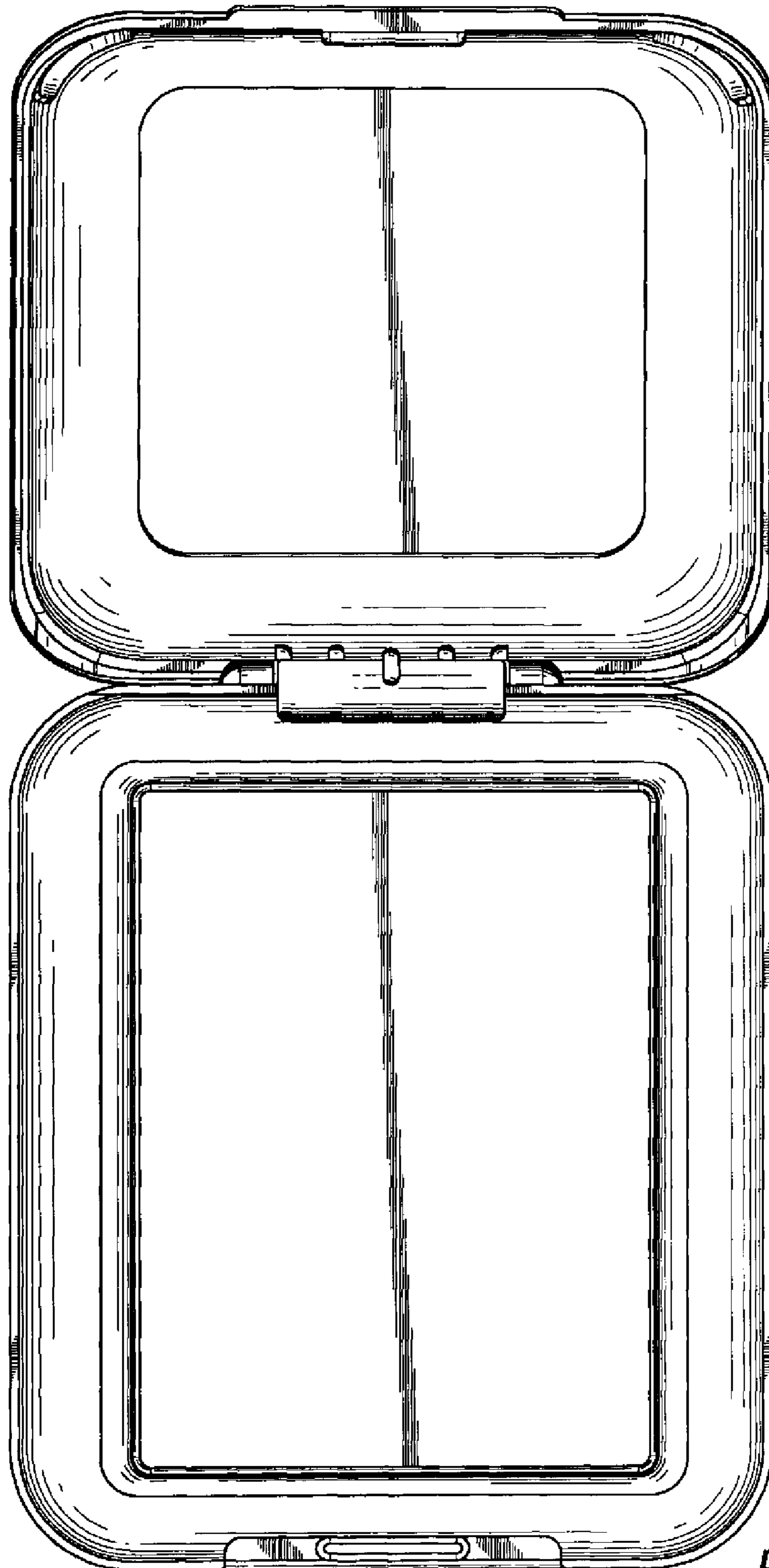


FIG. 12



FIG. 13

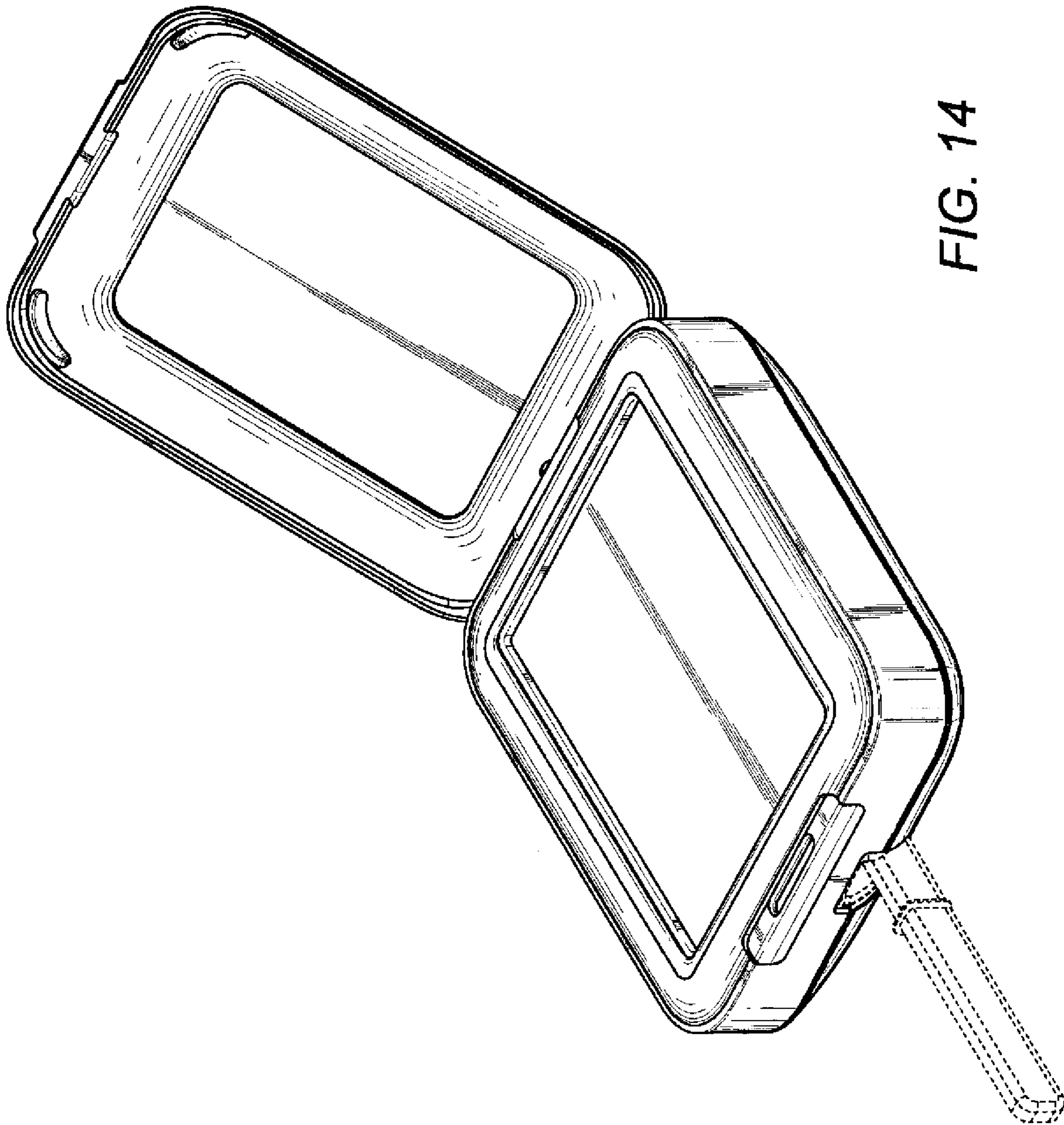


FIG. 14